

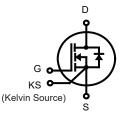
## DACMI150N120BZK3

#### Silicon Carbide Enhancement Mode MOSFET

#### **Features**

- ♦ V<sub>DSS</sub> = 1200V
- ightharpoonup R<sub>DS(ON)</sub> Tpy. 14 mΩ@ V<sub>GS</sub> = 15V
- Fully Avalanche Rated
- Pb Free & RoHS Compliant
- ♦ Isolation Type Package
- Electrically Isolation base plate

## Preliminary





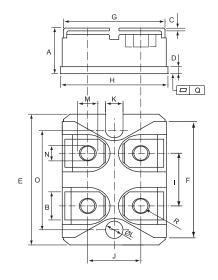
Dimensions in inches and (millimeters)

## **Applications**

- Solar Inverters
- Switch Mode Power Supplies
- **Power Converters**
- **Battery Chargers**
- Motor Drive

#### Absolute Maximum Ratings (Tc=25°C unless otherwise noted)

Parameter		Symbol	Ratings	Unit
Drain-Source Voltage		V <sub>DS</sub>	1200	V
Gate-Source Voltage		V <sub>GS</sub>	-4/+15	V
Drain Current-Continuous	@ T <sub>C</sub> =25°C @ T <sub>C</sub> =100°C	ΙD	150 100	Α
Drain Current-Pulsed	@ T <sub>C</sub> =25°C	I <sub>DM</sub>	300	Α
Maximum Power Dissipation		P <sub>D</sub>	600	w
Storage Temperature Range		T <sub>STG</sub>	-55 to +175	°C
Operating Junction Temperature Range		T <sub>VJ</sub>	-55 to +175	°C
Thermal Resistance, Junction-to-Case		$R heta_Jc$	0.25	°C/W
Isolation Voltage (A.C. 1 minute) between All Terminals and Baseplate		Viso	2500	٧
Mounting torque (M4 Screw)	To heatsink To terminals	M d	1.3 1.1	Nm



DIMENSIONS						
	INCHES		MM			
	MIN	MAX	MIN	MAX		
Α	0.460	0.483	11.68	12.28		
В	0.307	0.323	7.80	8.20		
С	0.030	0.033	0.75	0.85		
D	0.071	0.081	1.80	2.05		
Е	1.488	1.504	37.80	38.20		
F	1.248	1.260	31.70	32.00		
G	0.917	0.957	23.30	24.30		
Н	0.996	1.008	25.30	25.60		
1	0.579	0.602	14.70	15.30		
J	0.492	0.516	12.50	13.10		
K	0.161	0.169	4.10	4.30		
L	0.161	0.169	4.10	4.30		
М	0.181	0.197	4.60	5.00		
N	0.165	0.181	4.20	4.60		
0	1.181	1.197	30.00	30.40		
Q	-0.002	0.004	-0.05	0.10		
R	M4*8					



# DACMI150N120BZK3

### Electrical Characteristics @ Tc =25°C (unless otherwise specified)

Parameter	Symbol	Conditions	Min.	Тур.	Max.	Unit			
OFF Characteristics									
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V · I <sub>D</sub> =0.1mA	1200	-	-	٧			
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> =0V · V <sub>DS</sub> =1200V	-	1	50	μA			
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =15V , V <sub>DS</sub> =0V	-	1	200	nA			
ON Characteristics									
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = 27mA$	2.0	2.5	3.8	٧			
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =15V , I <sub>D</sub> =80A	-	14	18	mΩ			
Transconductance	<b>g</b> fs	V <sub>DS</sub> = 20V · I <sub>D</sub> =80A	-	68	-	S			
Internal Gate Resistance	R <sub>G(int.)</sub>		-	1.2	-	Ω			
Dynamic Characteristics									
Input Capacitance	C <sub>iss</sub>		-	6300	-	pF			
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> =1000V	-	260	-				
Reverse Transfer Capacitance	C <sub>rss</sub>	V <sub>GS</sub> =0V Freq.=100kHz	-	16	-				
Coss Stored Energy	E <sub>oss</sub>		-	150	-	μJ			
Turn-On Switching Energy	Eon	V <sub>DS</sub> =800V , V <sub>GS</sub> =-4V/+15V	-	1380	-	μJ			
Turn-Off Switching Energy	E <sub>off</sub>	I <sub>D</sub> =80A,R <sub>G(ext)</sub> =2.0Ω L=100μH	-	210	-				
Switching Characteristics									
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DS</sub> =800V	ı	34	-	- ns			
Rise Time	t <sub>r</sub>	$V_{GS}$ =-4/+15V $I_D$ =80A $R_{G(ext)}$ =2.0 $\Omega$	-	33	-				
Turn-Off Delay Time	t <sub>d(off)</sub>		-	50	-				
Fall Time	t <sub>f</sub>	L=100µH	ı	11	-				
Total Gate Charge	Qg	V <sub>DS</sub> =800V	ı	250	-	nC			
Gate to Source Charge	$\mathbf{Q}_{gs}$	V <sub>GS</sub> =-4/+15V	-	76	-				
Gate to Drain Charge	$\mathbf{Q}_{gd}$	I <sub>D</sub> =80A	ı	98	-				
Body Diode Characteristics									
Inverse Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> =-4V , I <sub>SD</sub> =40A	-	4.0	-	V			
Continuous Diode Forward Current	Is	V <sub>GS</sub> =-4V	-	-	100	Α			
Reverse Recovery Time	T <sub>rr</sub>	V <sub>GS</sub> =-4V	•	24	-	ns			
Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>SD</sub> =80A , V <sub>R</sub> =800V,	-	630	-	nC			
Peak Reverse Recovery Current	I <sub>rrm</sub>	dif/dt=4200A/μs	-	48	-	Α			





Fig 1. Output Characteristics, T<sub>J</sub> = -55°C

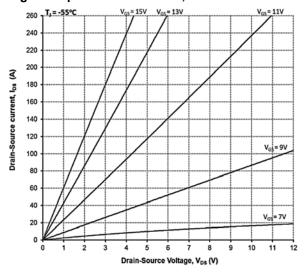


Fig 3. Output Characteristics, T<sub>J</sub> = 175°C

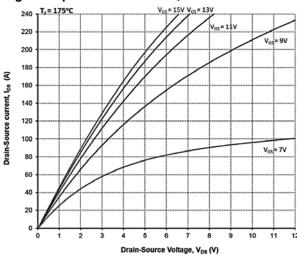


Fig 5. On-Resistance vs. Drain Current For Various Temperatures

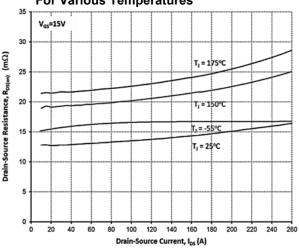


Fig 2. Output Characteristics, T<sub>J</sub> = 25°C

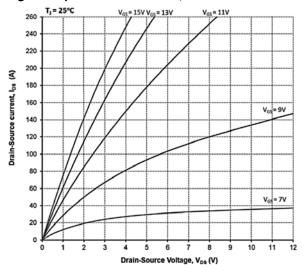


Fig 4. On-Resistance vs. Temperature

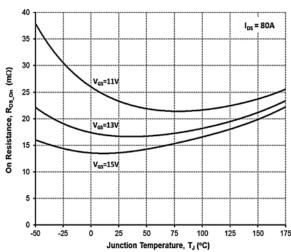


Fig 6. Transfer Characteristic For Various Junction Temperatures

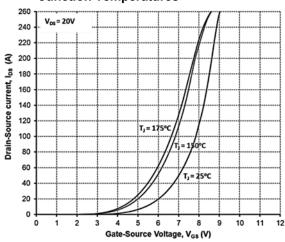






Fig 7. Threshold Voltage vs. Temperature

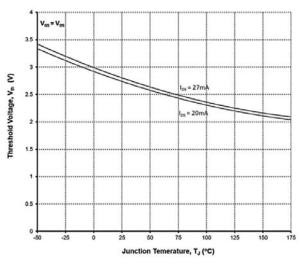


Fig 9. Body Diode Characteristics @ 25°C

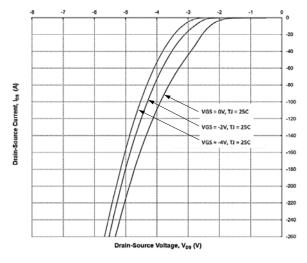


Fig 11. Gate Charge Characteristics

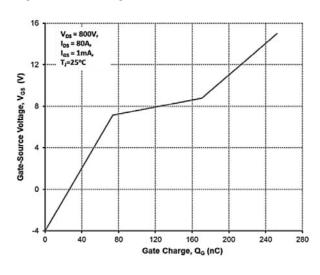


Fig 8.Body Diode Characteristics @ -55°C

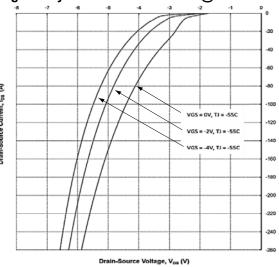


Fig 10. Body Diode Characteristics @ 175°C

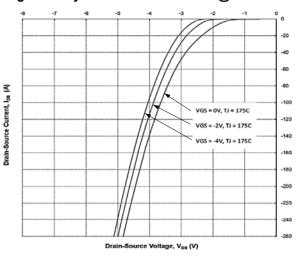


Fig 12. Quadrant Characteristics @ -55°C

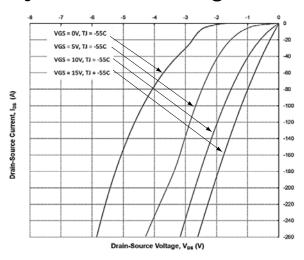






Fig 13. Quadrant Characteristics @ 25°C

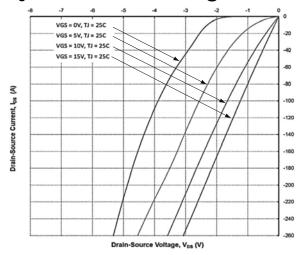


Fig 15. Output Capacitor Stored Energy

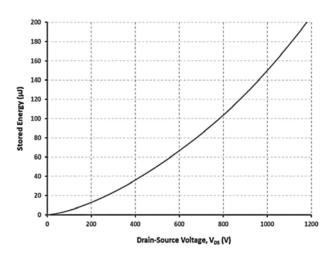


Fig 17. Capacitances vs. Drain-Source Voltage (0-1200V)

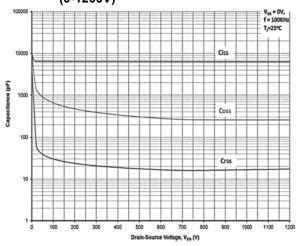


Fig 14. Quadrant Characteristics @ 175°C

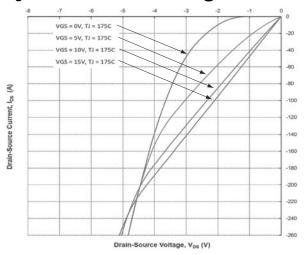


Fig 16. Capacitances vs. Drain-Source Voltage (0-200V)

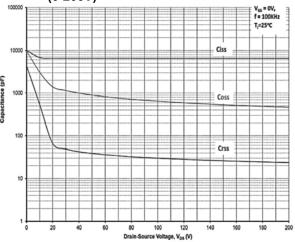


Fig 18. Continuous Drain Current (MOSFET) vs. Case Temperature

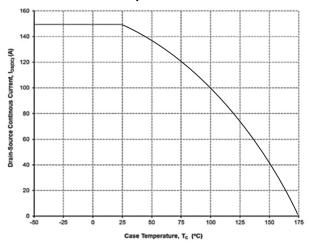






Fig 19. Maximum Power Dissipation Derating vs. Case Temperature

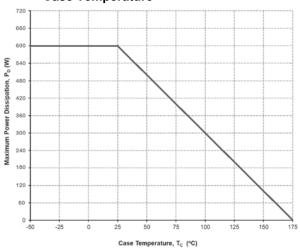


Fig 21. Safe Operating Area

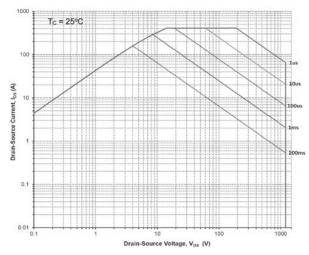


Fig 23. Switching Energy vs External Gate Resistor

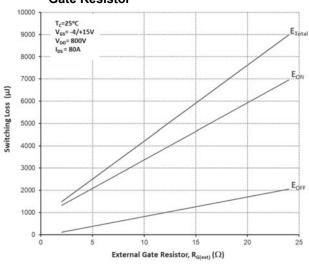


Fig 20. Transient Thermal Impedance (Junction to Case)

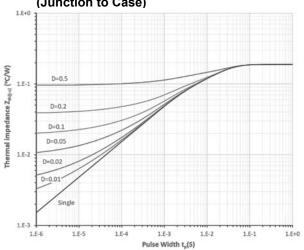


Fig 22. Switching Energy vs Drain Current

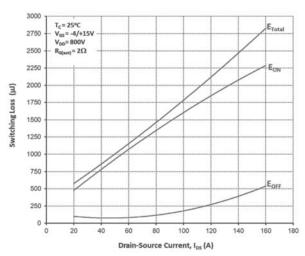
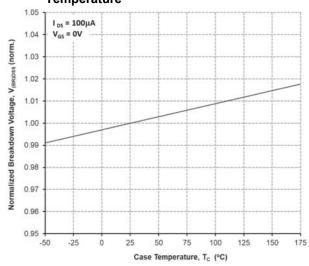


Fig 24. Normalized Breakdown Voltage vs Temperature





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